

ABSTRACT

A static CT apparatus and a CT inspection method. The apparatus includes one or more inspection assemblies, each inspection assembly including: a distributed multi-point source (S) configured to emit radiation beams; a detector (DT) disposed opposite to the distributed multi-point source to receive the radiation beams emitted by the distributed multi-point source, where the distributed multi-point source and the detector define an inspection channel; and a grating (G0, G1, G2) arranged in the inspection channel and between the distributed multi-point source and the detector. The grating is provided with a periodic structure configured to diffract the radiation beams to generate an interference fringe.